

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Custom Calibration Solutions, LLC

535 US HWY 130, Robbinsville, NJ, 08691

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2017 And meets the requirements of ANSI/NCSL Z540-1-1994

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Optical Calibration (As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen President

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084 Initial Accreditation Date: Issue Date: Ex September 27, 2022 January 29, 2024 Feb Accreditation No.: Certificate No.: 61599 L24-88

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: <u>www.pjlabs.com</u>

Expiration Date:

February 28, 2026



Certificate of Accreditation: Supplement

Custom Calibration Solutions, LLC

535 US HWY 130, Robbinsville, NJ, 08691 Contact Name: Dustin Williams Phone: 609-530-9000

Accreditation is granted to the facility to perform the following calibrations:

Optical			
MEASURED INSTRUMENT,	RANGE OR NOMINAL DEVICE	CALIBRATION AND	CALIBRATION
QUANTITY OR GAUGE	SIZE AS APPROPRIATE	MEASUREMENT	EQUIPMENT
		CAPABILITY EXPRESSED	AND REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Optical Wavelength x ^F	1 530 nm	0.000 2 nm	Reference Wavelength
			Standards monitored with
			Wavelength meter
			(OEM Methods)

- 1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
- 2. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location.